

Notice of References Cited

Application/Control No.

09/684,904

Applicant(s)/Patent Under

Reexamination

KON ET AL.

Examiner

THANH V TRAN

Art Unit

2814

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
	A	US-5,874,750	02-1999	Yanagisawa et al.	257	133
	B	US-				
	C	US-				
	D	US-				
	E	US-				
	F	US-				
	G	US-				
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